

27th RD50 Workshop (CERN)

Wednesday 2 December 2015

Defect Characterization - 6/2-024 - BE Auditorium Meyrin (11:20 - 13:20)

time	[id] title	presenter
11:20	[44] Development of the space oriented vacancy – interstitial cluster model	ZASINAS, Ernestas
11:40	[8] TSC measurements on 200 μm pad diodes, irradiated with 23 MeV protons [Wednesday]	DONEGANI, Elena
12:00	[12] Remarks on the thermally stimulated current measurement	VAITKUS, Juozas
12:20	[4] Effect of proton fluence on radiation defect structure of high-purity silicon for particle detectors	Prof. KAMINSKI, Pawel
12:40	[6] Carrier lifetime variations in pion irradiated and annealed Si	GAUBAS, Eugenijus
13:00	[29] Discussion on Defect Characterization	MOLL, Michael